

Challenges of reliability assessment and enhancement in autonomous systems

Jenihhin, Maksim; Sonza Reorda, Matteo; **Balakrishnan, Aneesh**; Alexandrescu, Dan 2019 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT 2019) 2019 / 6 p <https://doi.org/10.1109/DFT.2019.8875379>

Composing graph theory and deep neural networks to evaluate SEU type soft error effects

Balakrishnan, Aneesh; Lange, Thomas; Glorieux, Maximilien; Alexandrescu, Dan; **Jenihhin, Maksim** 9th Mediterranean Conference on Embedded Computing (MECO'2020), Budva, Montenegro, 8-11 June 2020 2020 <https://doi.org/10.1109/MECO49872.2020.9134279>

Enabling cross-layer reliability and functional safety assessment through ML-based compact models

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Gate-level graph representation learning : a step towards the improved stuck-at faults analysis

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Machine learning clustering techniques for selective mitigation of critical design features

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Machine learning to tackle the challenges of transient and soft errors in complex circuits

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Modeling gate-level abstraction hierarchy using graph convolutional neural networks to predict functional de-rating factors

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Modeling soft-error reliability under variability

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On antagonism between side-channel security and soft-error reliability in BNN inference engines

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On the estimation of complex circuits functional failure rate by machine learning techniques

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RESCUE EDA Toolset for interdependent aspects of reliability, security and quality in nanoelectronic systems design

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The validation of graph model-based, gate level low-dimensional feature data for machine learning applications

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Understanding multidimensional verification : where functional meets non-functional

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